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Applicant(s)/Patent under Reexamination

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Examiner

Art Unit

Paula W. Klimach

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SEARCHED			
Class	Subclass	Date	Examiner
713	162, 186, 176	9/2/2005	PWK
382	100, 199	9/22/2005	PWK
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO' (INCLUDING SEARCH		)
	DATE	EXMR
EAST	9/2/2005	PWK
IEEE	9/2/2005	PWK
Google	9/2/2005	PWK
Continuity Data	9/2/2005	PWK
Invnetor Name Search	9/2/2005	PWK